1/25/2008

RELIABILITY MONITOR REPORT
FOR

TSMC 0.35µm Silicon Gate CMOS

MAXIM Integrated Products

120 San Gabriel Dr.
Sunnyvale, CA 94086

This Report was prepared by
Maxim Reliability Engineering

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX1472AKA+	MAX4714EXT+	MAX7033EUI+	MAX7044AKA+	MAX9205EAI
MAX9206EAI+	MAX9218ECM+			

The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 93209 FITS: 1.2

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between and .

Process Information:

Process Description: TSMC 0.35µm Silicon Gate CMOS

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	FA NO
HIGH TEMP OP LIFE	0528	MAX9205EAI	135C, 5.25V	1000 HRS	80	0	
		MAX9206EAI+	135C, 5.25V	1000 HRS	78	0	
HIGH TEMP OP LIFE	0537	MAX4714EXT+	135C, 5.25V	1000 HRS	45	0	
			135C, 5.25V	1000 HRS	45	0	
			135C, 5.25V	1000 HRS	44	0	
HIGH TEMP OP LIFE	0545	MAX9218ECM+	135C, 5.25V	1000 HRS	47	0	
HIGH TEMP OP LIFE	0612	MAX7044AKA+	135C, 5.25V	1000 HRS	48	0	
HIGH TEMP OP LIFE	0614	MAX1472AKA+	135C, 5.25V	1000 HRS	46	0	
HIGH TEMP OP LIFE	0616	MAX7033EUI+	135C, 5.25V	1000 HRS	48	0	
				Total:		**0**	

FAILURE RATE: MTTF (YRS): 93209 FITS: 1.2